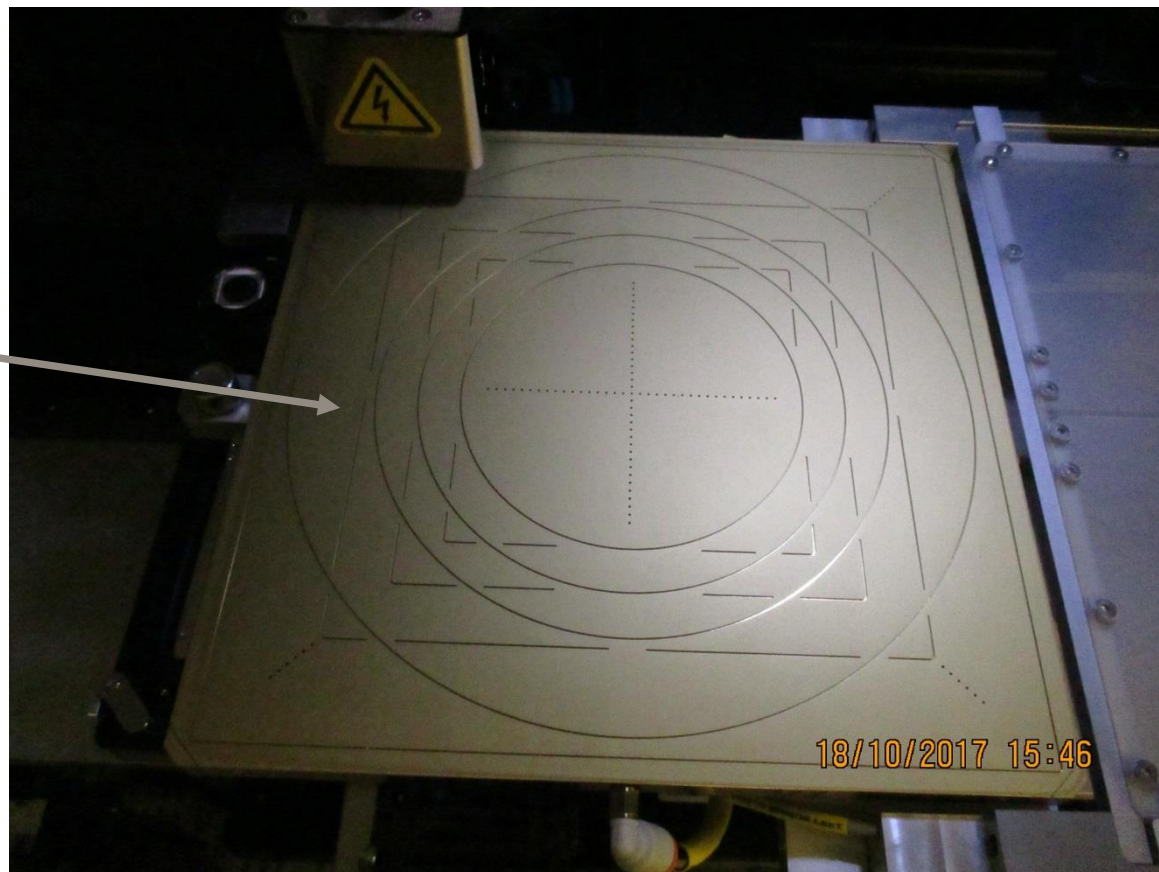


# Positioning stage for capacitance-voltage measurements

L3999 Fall2017– 3D printing course  
Guillaume von Gastrow

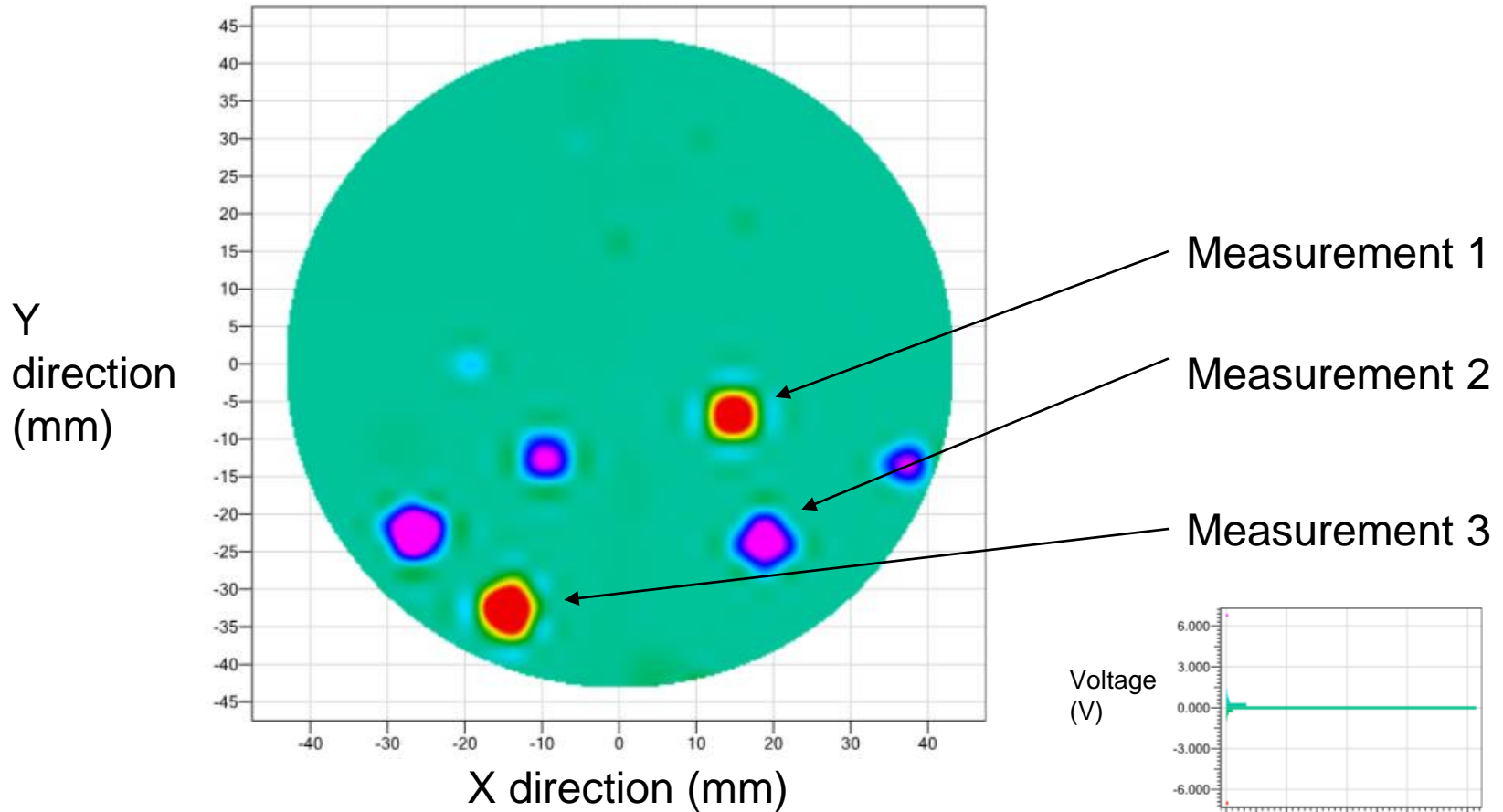


# Electrical characterization tool for silicon wafers



# Problem: samples remain locally charged after a measurement

Surface charge map



# Requirements

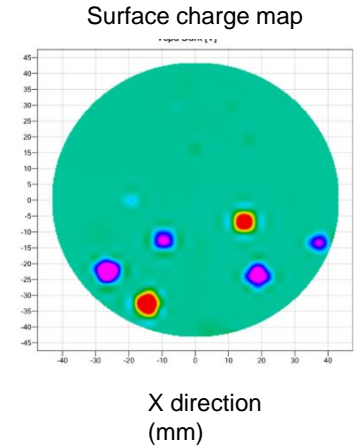
- Sometimes we want to:

1. perform measurements in different spots

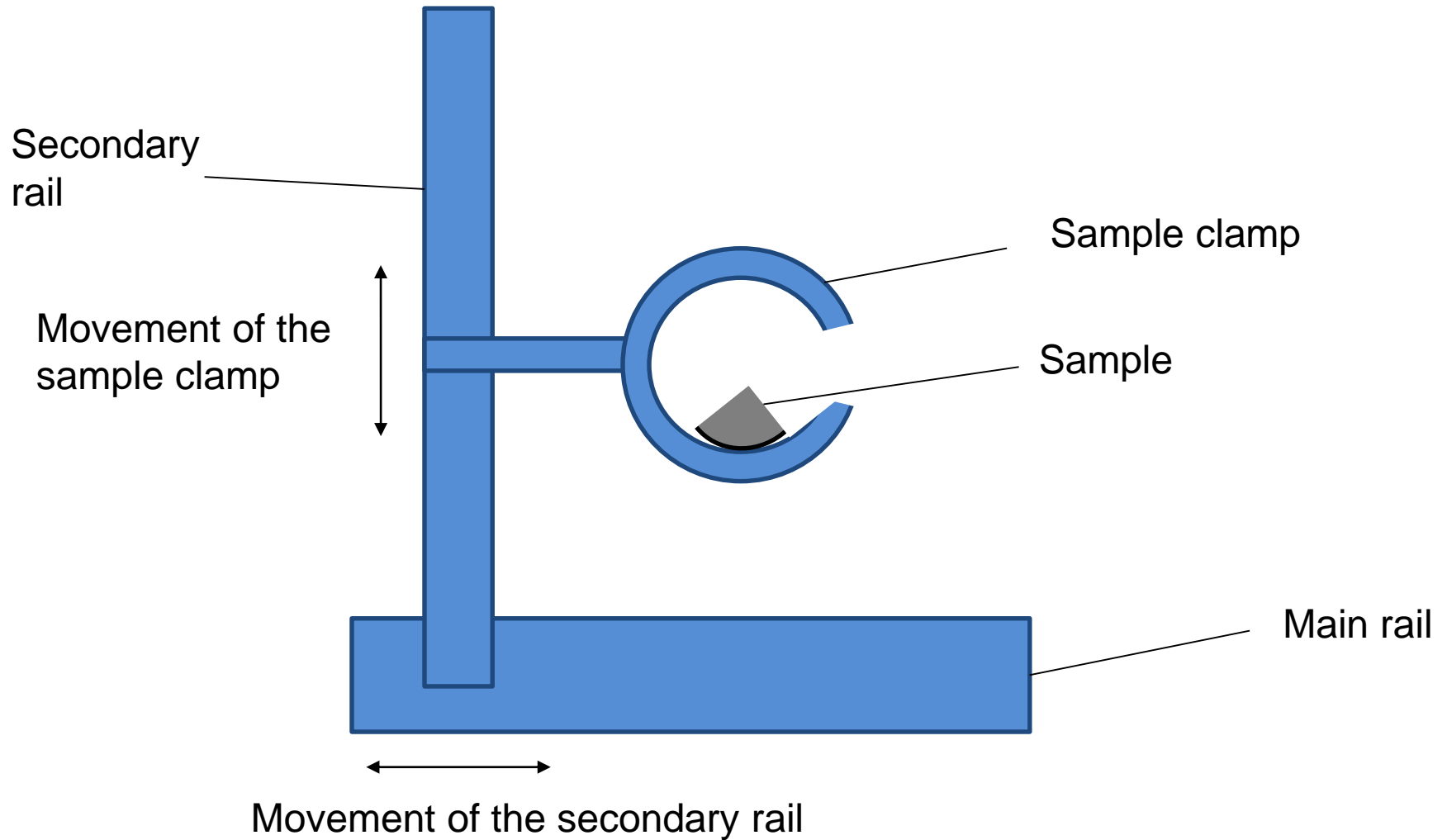
2. measure exactly the same spot as before

→ The sample must be placed accurately on the stage

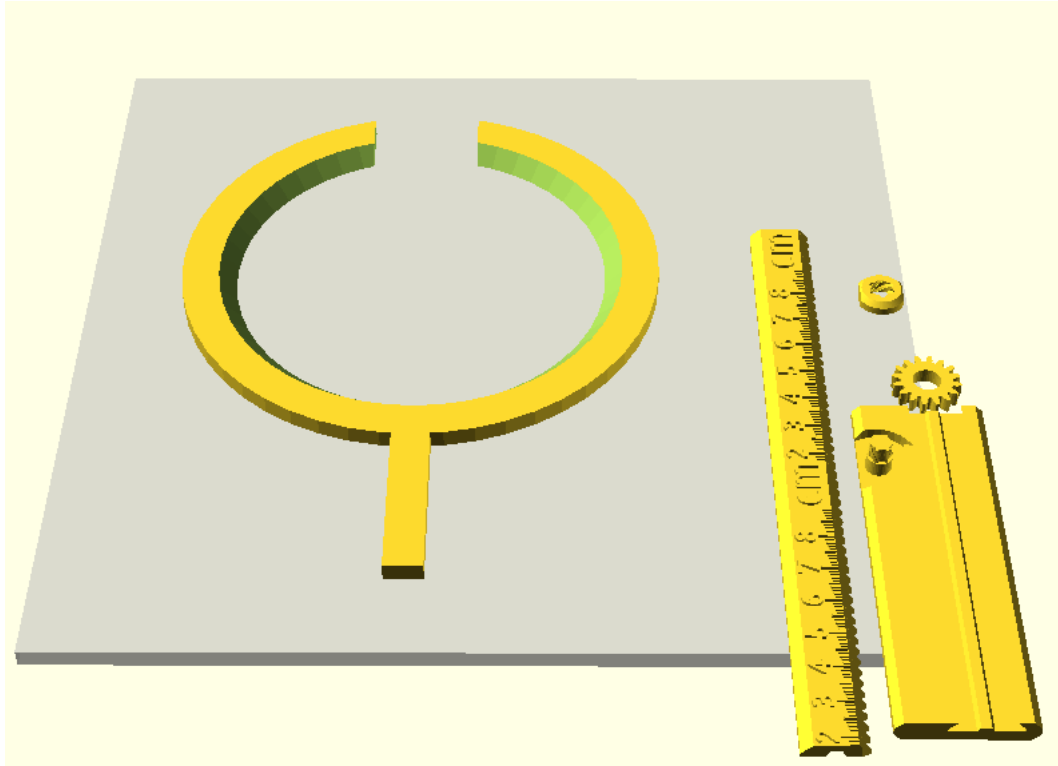
Y  
direction  
(mm)



# Design of an accurate sample positioning tool



# Current OpenSCAD design (still in process)



# First prototype of moving rail



To be  
continued...